The Texas A&M University System

ORGANIZATION

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DEPARTMENT

Department	02MSEN
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Ship-to-Address	Giesecke Engineering & Research Bldg. 1611 1617 Research Parkway College Station, TX 77843

BID INFORMATION

Description	iMicro, NanoFlip & Accessories		
Bulletin Desc.			
Bid Number	AM02-17-B000766	Bid Opening Date	01/05/2017 2:00 PM
Bid Type	Open Market	Type Code	Invitation for Bid
Alternate Id	39599AF	Fiscal Year	2017
		Available Date	11/14/2016 10:53 AM
Pre-Bid Conference			
Attachments	Bid Information - B000766.pdf Substitute W9 - New - February 19 2016~43.pdf Terms and Condtions (NEW) - All Departments~57.pdf		

AMENDMENTS

ITEMS

Item	Description	Quantity	Unit	Unit Price	Total
1.000	OBIA-1044 - iMicro Nanoindenter System *Displacement measurement: capacitive gauge *Displacement range: 80 microns *Displacement resolution (electronic): 0.04 nm *Typical noise <0.25 nm	1.00	LOT		
2.000	OBIA-1143-0 - InForce 50 Option for iMicro *Displacement measurement: capacitive gauge *Displacement range: 50 microns *Displacement resolution (electronic): 0.02 nm *Typical noise < 0.1 nm *Load application: coil/magnet *Maximum Load: 50 mN *Load resolution: 3 nN *Loading column mass: <150mg *Typical indenter normal stiffness: 80 N/m *Damping coefficient: 0.05 N-s/m *Typical resonant frequency: 120 Hz	1.00	EA		
3.000	MET-0001 - User Method Development for InView To provide for editing and creating methods for instrument operations and analysis	1.00	EA		
4.000	SMA-14115 - NanoFlip Mechanical Properties Microprobe Incorporates the following: *Inview software, InQuest Controller, InForce 50 Actuator, and integrated Dynamics. An additional 90 degree motor-controlled rotation axis which will allow the sample to be oriented either perpendicular to the SEM/FIB or Optic axis or perpendicular to the Actuator for mechanical property testing. To operate seamlessly in either compressive or tensile modes. *Displacement Measurement: Capacitive Gauge *Displacement Range: 50um *Displacement Resolution (Electronic): 0.02nm	1.00	EA		

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	*Typical Noise: <0.1 nm *Load Application: Electromagnetic *Maximum Load: 50mN *Load Resolution: 3nN *Maximum Load: 50mN *Load Resolution: 3nN *Data Acquisition Rate: 100 kHz *Closed Loop CPU Control Rate: 500 Hz *Dynamic Excitation Frequencies 0.1 Hz - 1 kHz *Travel: >5mm *Minimum Step Size: <= 10nm *Axial Stiffness: >8E+5 N/m				
5.000	INVF-1160 - NanoBlitz 4D Mechanical Property Tomography To utilize the InForce 50 Actuator to perform 4D map testing on materials with low E/H and high E (>3GPa) with a Berkovich tip. To perform indents in 5-10 seconds per indent up to 1000 indents (30x30 array), and to provide E, H, S as a function of depth for each indent in the array)	1.00	EA		
6.000	INVA-0864-0 - Thin Film Method Pack (Hard on Soft) Includes one (1) hard film on soft substrate reference standard, and test methods for evaluation of thin film properties	1.00	EA		
7.000	INVA-1048-0 - Polymer Method Pack Includes one (1) 50um dia Flat Punch End, 90 degree Conical Diamond, Conductive Tip, along with one (1) viscoelastic reference standard, and test methods for evaluation of viscoelastic properties	1.00	EA		
8.000	INVF-1281 - Scratch Method Pack Enables scratch capability by providing one Method as well as a Cube Corner tip Maximum Scratch Load: 10uN Maximum Scratch Load: 50 - 100 mN Maximum Displacement: 20 - 40 um Maximum Scratch Speed: 500 um/s Maximum Scratch DEistance 2.5 mm	1.00	EA		
9.000	POLY-0001 - Polymer Test Chamber for NanoFlip -20 degree C to 100 degree C temperature chamber for NanoFlip, allows use of inert gas, includes all pumps, fixtures, optical microscope with focus axis, and isolation chamber	1.00	EA		
10.000	2DMA-0001 - 2D Multiaxis Indenter Option NanoFlip Consists of mechanical adaptation to connect two InForce 50 actuators for synchronous testing in two dimensions. The 2D Indenter Assembly is interchangeable with the InForce 50 on the NanoFllip platform	1.00	EA		
11.000	CUSTOM - 2D Tester Standalone Run Kit The 2D Tester Standalong Run Kit includes one InForce 50 actuator, one InQuest controller, one CPU with bundled InView software, along with the electronic and mechanical adapters which allow integration with a standard NanoFlip motion system. This allows the 2D Multiaxis Indenter Option to run independently of the NanoFlip	1.00	EA		
12.000	SVC-0003 - Site Service Contract, 1 Year, 2-4 Instruments To include software updates, 30% discount on repairs, free simulation copies of software, phone support up to 3 support instances, 10% discount on consumables, tipes, and options. Valid for multiple instruments at a single site.	1.00	EA		